

## **CISPR TR 16-4-3**

Edition 2.1 2007-01 CONSOLIDATED VERSION

# TECHNICAL REPORT

INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

Specification for radio disturbance and immunity measuring apparatus and methods –

Part 4-3: Uncertainties, statistics and limit modelling – Statistical considerations in the determination of EMC compliance of mass-produced products

INTERNATIONAL ELECTROTECHNICAL COMMISSION

ICS 33.100.10; 33.100.20 ISBN 2-8318-8915-4

Warning! Make sure that you obtained this publication from an authorized distributor.

## CONTENTS

| FO   | REW   | ORD   |   | 3  |
|--|---|---|---|----|
| 1  | Scor  | oe  |   | 5  |
| 2  | Normative references  |   |   |    |
| 3  | Terms, definitions and symbols                                      |   |   |    |
| 4  | General requirements  |   |   |    |
|  | 4.1 Limits  |   |   |    |
|  | 4.2   |   |   |    |
| 5  | Emission measurements   |   |   |    |
|  | 5.1   | 5.1 Test based on the non-central <i>t</i> -distribution      |   |    |
|  | 5.2   | 5.2 Test based on the binomial distribution                   |   |    |
|  | 5.3 Test based on an additional acceptance limit                    |   |   | 9  |
|  | 5.4 Additional sampling in case of non-compliance                   |   |   | 10 |
|  | 5.5   | 5.5 Properties of the different methods that can be used      |   |    |
|  | 5.6 Compliance criteria and measurement instrumentation uncertainty |   |   | 12 |
| 6  | Immunity tests  |   |   | 12 |
|  | 6.1   | 6.1 Application of the CISPR 80 %/80 % rule to immunity tests |   |    |
|  | 6.2 Application guidelines  |   |   | 12 |
| Anı  | nex A   | (informative)   | Statistical considerations in the determination of limits of radio                            |    |
|  |   |   |   | 14 |
|  |   |   | An analytical assessment of statistical parameters of radio of an incompletely defined sample | 22 |
| Annex C (informative) Test based on an additional acceptance limit         |   |   |   |    |
| Annex D (informative) Estimation of the acceptance probability of a sample |   |   |   |    |
|  |   | ,   |   |    |
| Bib  | liogra  | phy   |   | 36 |

#### INTERNATIONAL ELECTROTECHNICAL COMMISSION

## SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 4-3: Uncertainties, statistics and limit modelling – Statistical considerations in the determination of EMC compliance of mass-produced products

#### **FOREWORD**

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC provides no marking procedure to indicate its approval and cannot be rendered responsible for any equipment declared to be in conformity with an IEC Publication.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

This consolidated version of the official IEC Standard and its amendment has been prepared for user convenience.

CISPR 16-4-3 edition 2.1 contains the second edition (2004) [documents CISPR/A/491/DTR and CISPR/A/492/DTR and CISPR/A/507/RVC and CISPR/A/508/RVC] and its amendment 1 (2006) [documents CISPR/A/666/DTR and CISPR/A/691/RVC].

A vertical line in the margin shows where the base publication has been modified by amendment 1.

The main task of IEC technical committees is to prepare International Standards. However, a technical committee may propose the publication of a technical report when it has collected data of a different kind from that which is normally published as an International Standard, for example "state of the art".

CISPR 16-4-3, which is a technical report, has been prepared by CISPR subcommittee A: Radio interference measurements and statistical methods.

This second edition of CISPR 16-4-3 cancels and replaces the first edition published in 2003 and constitutes a technical revision. It includes a new mathematical approach for the application of the 80%/80% rule, based on a method involving an additional acceptance limit. The mathematical basis for this new method is also provided. Furthermore, an additional test approach, based on the non-central t distribution and using frequency sub-ranges has been added as well, along with a description of the properties of all methods which are available at this point in time.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of the base publication and its amendments will remain unchanged until the maintenance result date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- · reconfirmed,
- withdrawn,
- · replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

## SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 4-3: Uncertainties, statistics and limit modelling – Statistical considerations in the determination of EMC compliance of mass-produced products

#### 1 Scope

This part of CISPR 16 deals with statistical considerations in the determination of EMC compliance of mass-produced products.

The reasons for such statistical considerations are:

- a) that the abatement of interference aims that the majority of the appliances to be approved shall not cause interference;
- b) that the CISPR limits should be suitable for the purpose of type approval of mass-produced appliances as well as approval of single-produced appliances;
- c) that to ensure compliance of mass-produced appliances with the CISPR limits, statistical techniques have to be applied;
- d) that it is important for international trade that the limits shall be interpreted in the same way in every country;
- e) that the National Committees of the IEC which collaborate in the work of the CISPR should seek to secure the agreement of the competent authorities in their countries.

Therefore, this part of CISPR 16 specifies requirements and provides guidance based on statistical techniques. EMC compliance of mass-produced appliances should be based on the application of statistical techniques that must reassure the consumer, with an 80 % degree of confidence, that 80 % of the appliances of a type being investigated comply with the emission or immunity requirements. Clause 4 gives some general requirements for this so-called 80 %/80 % rule. Clause 5 gives more specific requirements for the application of the 80 %/80 % rule to emission tests. Clause 6 gives guidance on the application of the CISPR 80 %/80 % rule to immunity tests. The 80 %/80 % rule protects the consumer from non-compliant appliances, but it says hardly anything about the probability that a batch of appliances from which the sample has been taken will be accepted. This acceptance probability is very important to the manufacturer. In Annex A, more information is given on acceptance probability (manufacturer's risk).

### 2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60050-161:1990, International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility
Amendment 1 (1997)
Amendment 2 (1998)

CISPR 16-4-2, Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Uncertainty in EMC measurements